Safe and Secure Embedded Systems

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Deadline for manuscript submissions:
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Message from the Guest Editors

This Special Issue solicits novel research in topics that include, but are not limited to:

- modeling of safety and security concerns in embedded systems
- interdependencies between safety and security in embedded systems
- integrated approaches safety and security
- security in safety-critical systems
- run-time mechanisms in hardware and software to support safety and security
- safety and security in parallel and/or heterogeneous computing platforms
- methods, tools, and techniques for modeling, design, and verification of safe and secure embedded systems
- implications of regulation and certification on safety and security in embedded systems
- thread and hazard analysis of hardware and software components
- fault tolerant designs for safe and secure embedded systems
- hardware and software co-design and specialization for safe and secure embedded systems

Welcome to contribute!

Special Issue

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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